

Status Update on the Activities on PASTA

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Outline

PASTA Readout Chain

Fixes for Known Bugs

New Developments

Data Analysis - Preliminary

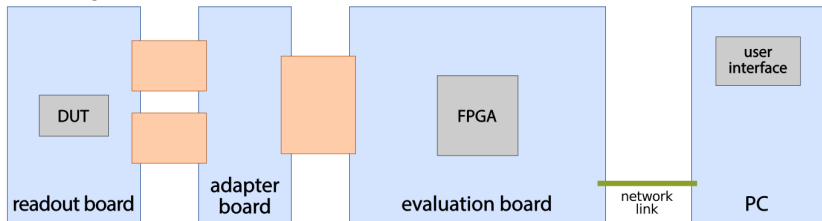
Summary

Outlook

JDRS: Jülich Digital Readout System

The basic components

Jülich Digital Readout System (JDRS).



Data conversion and communication with the PC:

- DUT: ToPix, **PASTA**
- evaluation board: Xilinx ML605 (Virtex-6 FPGA)
- firmware: VHDL

Configuration and data handling:

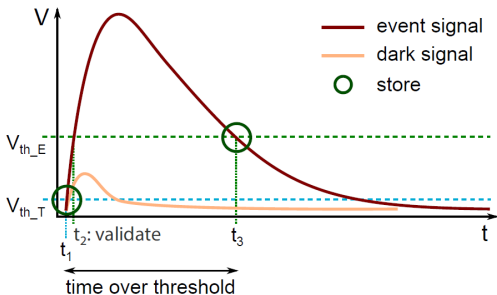
- PC
- software: C++
- **MVD readout framework (MRF)**
- **Qt-based GUI**

PASTA: PANDA Strip Asic

Free running readout chip for the strips

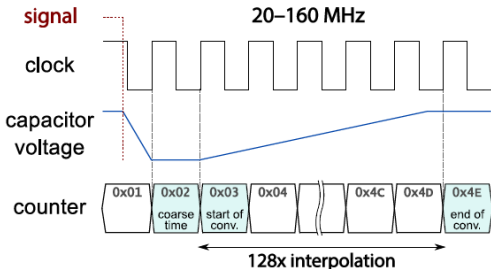
Concept: measurement of points in time based on two leading-edge discriminator outputs.

- Low threshold - time branch: resolve leading edge of pulse.
- High threshold - energy branch: falling edge, pulse length (i.e. deposited charge)



Timestamps

- Clock resolution: 6.25 ns (@160 MHz) - coarse timestamp.
- Enhanced resolution: up to 50 ps - fine timestamp.



- $t_{\text{coarse}} \rightarrow$ leading edge of the clk after threshold crossing.
- $t_{\text{fine}} \simeq t_{\text{eoc}}^1 - t_{\text{soc}}^2$

¹end of conversion

²start of conversion

Bug Fixes

Bugs reported @MVD meeting during June CM have been fixed:

- bug in channel configuration (address)
- bug on 10b/8b decoding (synchronization)
- problem on the transmission line (inversion)

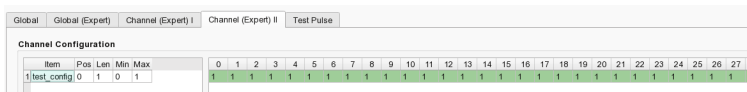
Another bug in the local configuration not visible during configuration, affected the behavior of the chip:

```
constant DEFAULT_CH_CONFIG : std_logic_vector(CH_CONFIG_SIZE-1 downto 0) :=
  '0'      & -- 41      finish config
-- analogue configuration
b"1010"   & -- 40..37 Iref_ratio, energy
b"1010"   & -- 36..33 Iref_ratio, time
b"00000"  & -- 32..28 HCLDAC_e
b"00000"  & -- 27..23 HCLDAC_t
'0'       & -- 22      not used
b"1000"   & -- 21..18 If
...

```

By default all channels are enabled in a test mode.
I.e. they all receive the test pulse.

ch_test_configuration → single channels to sensor or calibration circuit



The screenshot shows a software interface with several tabs: "Global", "Global (Expert)", "Channel (Expert) I", "Channel (Expert) II", and "Test Pulse". The "Channel Configuration" section is active, displaying a table with 28 columns and one row of data. The columns are numbered 0 to 27. The first row of data shows a value of 1 for all columns from 1 to 27, while column 0 has a value of 0.

Item	Pos	Len	Min	Max	0	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24	25	26	27
1 test_config	0	1	0	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	

- Define the type of injection.
- Scan a user define range of channels.
- Choose up to two parameters to sweep (at present, global thresholds and pulse amplitude available).

Channel Scanner

test pulse to TDC (digital)
 test pulse to front-end (analog)

ch start
ch stop
curr ch

two param scan

First Loop	Second Loop
HCGDACn	HCGDACp
start <input type="text" value="0"/>	start <input type="text" value="0"/>
stop <input type="text" value="15"/>	stop <input type="text" value="15"/>
step <input type="text" value="1"/>	step <input type="text" value="1"/>

Data Handling

- FPGA data handling:
 - 10b/8b decoded data stored in FIFO.
- Software data handling:
 - request data from fifo.
 - store raw data in ASCII file (hex).
 - convert data word into usable object.

DAQ FIFO data

pathname:

filename:

Save using:
 ASCII
 boost serial.

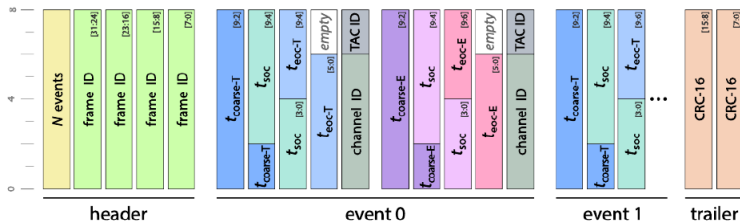
suppress comma words
 display frame indicator
 suppress empty frames

readout iterations

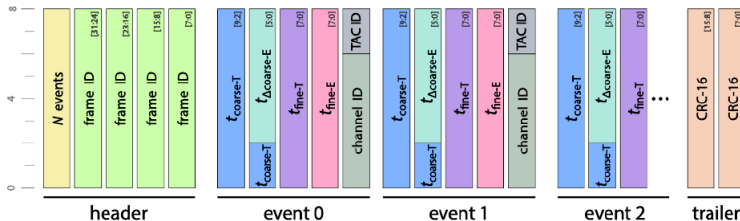
current iteration

- Suppress comma words
- Display frame indicator
- Suppress empty frames

Full mode: two words per event **not decoded in the software**.



Compact mode: one word per event **decoded in the software**.



Empty Frames Suppression

- Problem:

After the FIFO buffer(s) are completely filled
→ data loss inbetween two readout requests.

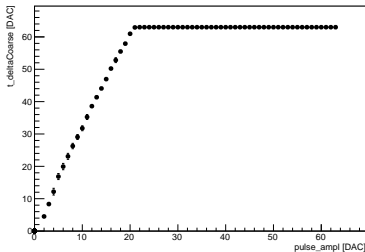
- Solution:

Different (more or less) complicated options to fix this.
Quick and efficient workaround for testing phase
→ suppression of empty frames @FPGA level.
⇒ Sufficient for high intensity beam?

Offline data analysis in ROOT.

- Import decoded data from ASCII file.
- Store it in a TTree.
- Several macros available for different analysis.

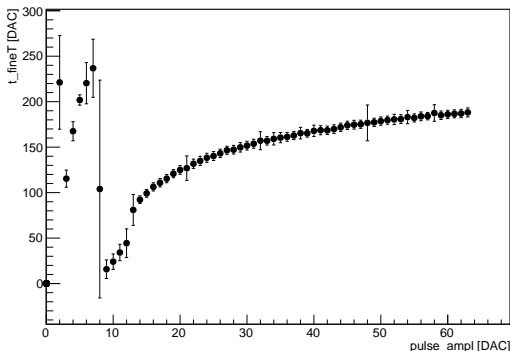
Rough estimation of the time over threshold: $t_{\Delta coarse} = t_{coarseE} - t_{coarseT}$



- Saturation at $t_{\Delta coarse} = 63$ due to compact mode:
→ value transmitted using only 6 bits.
- Maximum amplitude detectable @50 MHz: $1.3 \mu s$.
- Maximum amplitude detectable @160 MHz: $400 ns$.

Fine Time - Time Branch

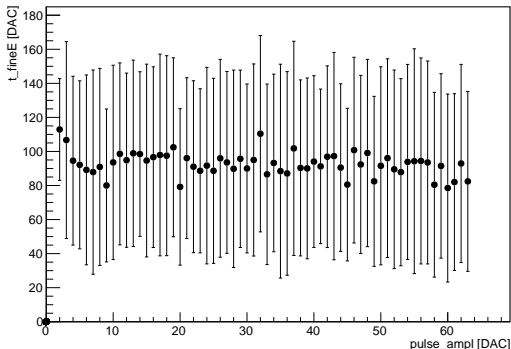
$$t_{fine} \simeq t_{eoc} - t_{soc}$$



- Discontinuity (probably) due to which clock edge is used for calculation (i.e. the first one after a falling edge).

Fine Time - Energy Branch

$$t_{\text{fine}} \simeq t_{\text{eoc}} - t_{\text{soc}}$$



- Falling edge slower than the rising edge.
- Susceptible to noise.
- Jitter in the timestamp.
- Quite big error bars. (?)

Threshold Scan - qualitative

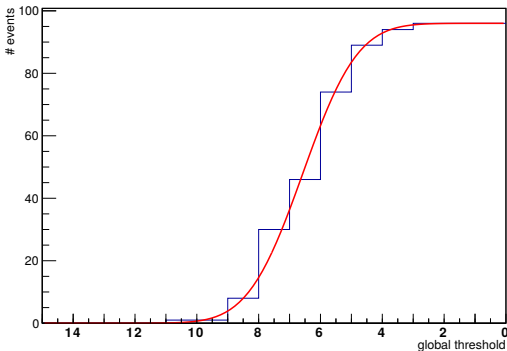
Global thresholds

- $\Delta_{th} = HCGDAC + -HCGDAC -$
→ midvalue of an interval with predefined amplitude.
- Sweep over Δ_{th} at fixed pulse amplitude.
- Expected: S-curve shape.
- Observed: box-like shape
→ for pulse amplitude > 2 the signal is already above threshold.

Threshold Scan - qualitative

Global thresholds

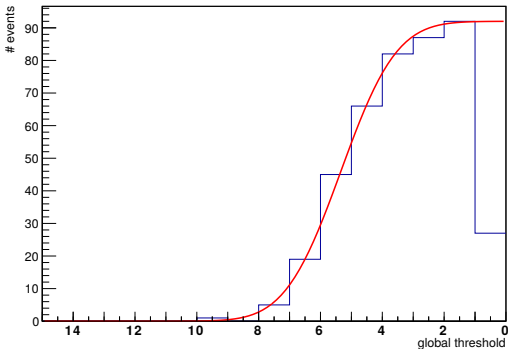
Pulse amplitude = 1



$$F(x) = \frac{n}{2} \left(1 + \operatorname{erf} \frac{(x - \mu)}{\sqrt{2} \cdot \sigma} \right) \quad \text{where} \quad \operatorname{erf} \frac{(x - \mu)}{\sqrt{2} \cdot \sigma} = \frac{2}{\pi} \int_0^x e^{-t^2} dt$$

Threshold Scan - qualitative

- Not all the channels behave the same → no threshold distribution.
- Events loss at small Δ_{th} → lower limit of interval below baseline.



Possible improvements:

- fine tuning with local thresholds
- adjusting the baseline voltage

- Development of the JDRS is ongoing.
- Tools for first analysis of data from PASTA available.
- Overall behavior of the chip still unclear (e.g. channels behave differently).
- Need input from the experts on how to tackle this problem.

- Calibration of the DAC for meaningful estimation of noise etc.
- Understand behavior of nasty channels.
- Continue analysis towards chip characterization.
- Continue developing JDRS with needed features.
- Implementation in the firmware of a test pulse with configurable phase shift wrt the clock.